

Notice of References Cited	Application/Control No. 10/551,901	Applicant(s)/Patent Under Reexamination MIURA ET AL.	
	Examiner Jeffrey T. Palenik	Art Unit 1615	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0058956	03-2004	Akiyama et al.	514/318
*	B	US-2003/0121453	07-2003	Iwahashi et al.	106/502
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1 323 786 A1	07-2003	EP	Iwahashi et al.	C09D 7/00
	O					
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	R					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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